SCBS012D - JULY 1988 - REVISED SEPTEMBER 1994

- State-of-the-Art BiCMOS Design Significantly Reduces I_{CC7}
- 3-State Outputs Drive Bus Lines or Buffer **Memory-Address Registers**
- P-N-P Inputs Reduce DC Loading
- Data Flow-Through Pinout (All Inputs on **Opposite Side From Outputs)**
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Plastic (N) and Ceramic (J) 300-mil DIPs

description

The SN54BCT540 and SN74BCT540A octal buffers and line drivers are ideal for driving bus lines or buffer memory-address registers. The devices feature inputs and outputs on opposite sides of the package that facilitate printed-circuitboard layout.

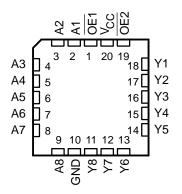
The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable (OE1 or OE2) input is high, all corresponding outputs are in the high-impedance state.

The SN54BCT540 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74BCT540A is characterized for operation from 0°C to 70°C.

OE1 1 20 V _{CC} A1 2 19 OE2 A2 3 18 Y1 A3 4 17 Y2 A4 5 16 Y3 A5 6 15 Y4 A6 7 14 Y5	SN74BCT540A DW OR N PACKAGE (TOP VIEW)									
A7 8 13 Y6 A8 9 12 Y7 GND 10 11 Y8	A1 [A2 [A3 [A4 [A5 [A6 [A8 [3 4 5 6 7 8 9	19 18 17 16 15 14 13 12	OE2 Y1 Y2 Y3 Y4 Y5						

SN54BCT540 ... J OR W PACKAGE

SN54BCT540 ... FK PACKAGE (TOP VIEW)



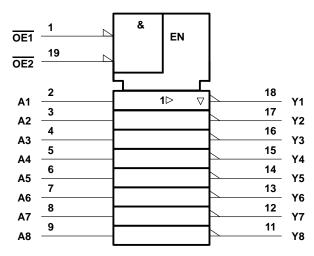
FUNCTION TABLE

		INPUTS	OUTPUT	
6	DE1	OE2	Α	Y
	L	L	L	Н
	L	L	Н	L
	н	х	Х	Z
	Х	Н	Х	Z

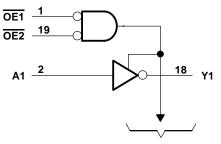
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

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logic symbol[†]



logic diagram (positive logic)



To Seven Other Channels

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}	– 0.5 V to 7 V
Input voltage range, VI (see Note 1)	– 0.5 V to 7 V
Voltage range applied to any output in the disabled or power-off state, VO	– 0.5 V to 5.5 V
Voltage range applied to any output in the high state, VO	$\dots \dots \dots - 0.5 \text{ V to V}_{CC}$
Current into any output in the low state: SN54BCT540	
SN74BCT540A	128 mA
Operating free-air temperature range, T _A : SN54BCT540	– 55°C to 125°C
SN74BCT540A	0°C to 70°C
Storage temperature range	– 65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

recommended operating conditions

		SN54BCT540			SN7	UNIT		
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
V_{IH}	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
IIК	Input clamp current			-18			-18	mA
ЮН	High-level output current			-12			-15	mA
IOL	Low-level output current			48			64	mA
Т _А	Operating free-air temperature	-55		125	0		70	°C



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST CONDITIONS		SN	I54BCT5	40	SN7			
PARAMETER			MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lı = –18 mA			-1.2			-1.2	V
		$I_{OH} = -3 \text{ mA}$	2.4	3.3		2.4	3.3		
VOH	V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2	3.2					V
		I _{OH} = -15 mA				2	3.1		
Ve	V _{CC} = 4.5 V	I _{OL} = 48 mA		0.38	0.55				V
VOL	VCC = 4.5 V	I _{OL} = 64 mA					0.42	0.55	v
lį	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
ЧΗ	V _{CC} = 5.5 V,	VI = 2.7 V			20			20	μA
۱ _{IL}	V _{CC} = 5.5 V,	V _I = 0.5 V			-0.6			-0.6	mA
IOZH	V _{CC} = 5.5 V,	V _O = 2.7 V			50			50	μΑ
IOZL	V _{CC} = 5.5 V,	$V_{O} = 0.5 V$			-50			-50	μA
IOS‡	V _{CC} = 5.5 V,	$V_{O} = 0$	-100		-225	-100		-225	mA
ІССН	V _{CC} = 5.5 V			20	30		20	30	mA
ICCL	V _{CC} = 5.5 V			45	71		45	71	mA
ICCZ	V _{CC} = 5.5 V			3	6		3	6	mA
Ci	V _{CC} = 5 V,	V _I = 2.5 V or 0.5 V		6			5		pF
Co	V _{CC} = 5 V,	V _O = 2.5 V or 0.5 V		10			10		pF

[†] All typical values are at V_{CC} = 5 V, T_A = 25°C.
[‡] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

switching characteristics (see Figure 1)

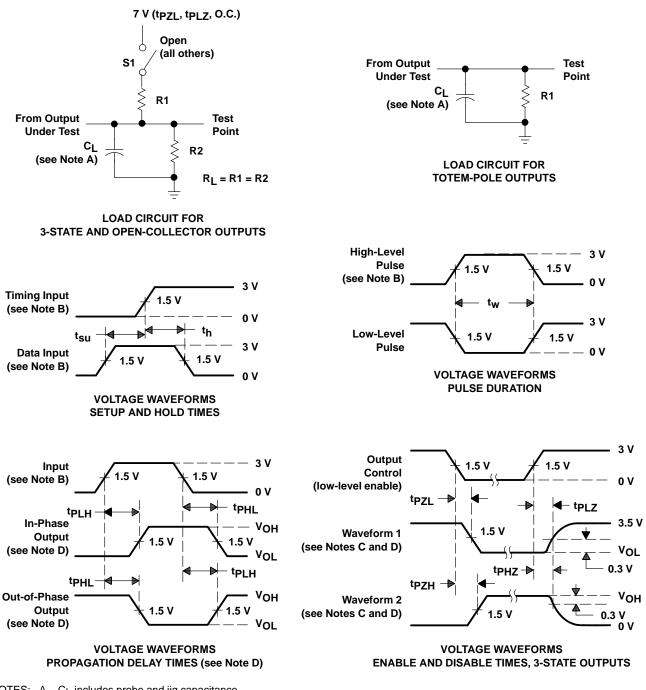
PARAMETER	FROM (INPUT)	TO (OUTPUT)	CI R´ R:	CC = 5 V = 50 p = 500 9 2 = 500 9 A = 25°C	F, Ω, Ω,	CL R1 R2	= 50 pF = 500 Ω 2 = 500 Ω	2,	9	UNIT	
			ΎΙ	BCT540		SN54B	CT540	SN74BC	T540A		
			MIN	TYP	MAX	MIN	MAX	MIN	MAX		
^t PLH	A	A	Y	2.5	4.1	5.8	1.9	7.2	2	6.9	
^t PHL			T	0.6	1.9	3.5	0.3	4.5	0.3	4	ns
^t PZH	OE	OE Y	V	4	6.8	8.9	4.1	10.4	3.3	10.1	ns
^t PZL			5	8	10	5.3	11.8	4.3	11.3	115	
^t PHZ	OE	Y	3.5	5.7	7.8	2.7	9.4	2.7	9	ns	
^t PLZ	UL UL	ř	3.8	5.5	7.4	3.5	8.9	3.5	8.5	115	

§ For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. CI includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, t_r = t_f \leq 2.5 ns, duty cycle = 50%. C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control.
 - Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one transition per measurement.
- E. When measuring propagation delay times of 3-state outputs, switch S1 is open.

Figure 1. Load Circuits and Voltage Waveforms



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